# TOSHIBA

TOSHIBA Field Effect Transistor Silicon P Channel MOS Type ( $L^2-\pi$ -MOSVI)

# **TPC8301**

Lithium Ion Battery Applications Portable Equipment Applications Notebook PCs

- Small footprint due to small and thin package
- Low drain-source ON resistance  $: R_{DS} (ON) = 95 \text{ m}\Omega (typ.)$
- High forward transfer admittance :  $|Y_{fs}| = 4 S (typ.)$
- Low leakage current  $: I_{DSS} = -10 \ \mu A \ (max) \ (V_{DS} = -30 \ V)$
- Enhancement-mode :  $V_{th} = -0.8 \sim -2.0 \text{ V} (V_{DS} = -10 \text{ V}, \text{ ID} = -1 \text{ mA})$

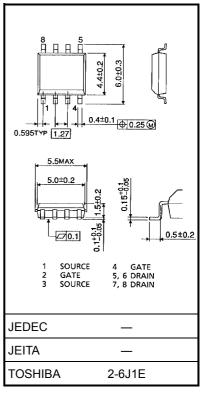
### Maximum Ratings (Ta = 25°C)

Char	acteristics	Symbol	Rating	Unit	
Drain-source vo	Itage	V <sub>DSS</sub>	-30	V	
Drain-gate volta	ge (R <sub>GS</sub> = 20 kΩ)	V <sub>DGR</sub>	-30	V	
Gate-source vol	tage	V <sub>GSS</sub>	±20	V	
Drain current	D C (Note 1)	۱ <sub>D</sub>	-3.5	А	
Dialiticulterit	Pulse (Note 1)	I <sub>DP</sub>	-14	A	
Drain power	Single-device operation (Note 3a)	P <sub>D (1)</sub>	1.5	W	
dissipation (t = 10 s) (Note 2a)	Single-devece value at dual operation (Note 3b)	P <sub>D (2)</sub>	1.0		
Drain power dissipation (t = 10 s) (Note 2b)	Single-device operation (Note 3a)	P <sub>D (1)</sub>	0.75		
	Single-devece value at dual operation (Note 3b)	P <sub>D (2)</sub>	0.45	W	
Single pulse ava	lanche energy (Note 4)	E <sub>AS</sub>	16	mJ	
Avalanche currei	nt	I <sub>AR</sub>	-3.5	А	
Repetitive avalar (Note	nche energy e 2a, Note 3b, Note 5)	E <sub>AR</sub>	0.10	mJ	
Channel tempera	ature	T <sub>ch</sub>	150	°C	
Storage tempera	ture range	T <sub>stg</sub>	-55~150	°C	

Note: For (Note 1), (Note 2a), (Note 2b), (Note 3a), (Note 3b), (Note 4) and (Note 5), please refer to the next page.

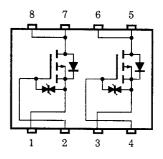
This transistor is an electrostatic sensitive device. Please handle with caution.





Weight: 0.080 g (typ.)

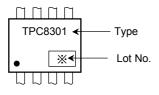
# **Circuit Configuration**



## **Thermal Characteristics**

Characteristics	Symbol	Max	Unit		
Thermal resistance, channel to embiant	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	83.3		
Thermal resistance, channel to ambient (t = 10 s) (Note 2a)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	125	°C/W	
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	167	C/VV	
(t = 10  s) (Note 2b)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	278		

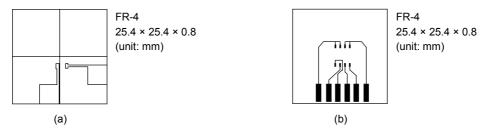
## Marking



Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2:

- a) Device mounted on a glass-epoxy board (a)
- b) Device mounted on a glass-epoxy board (b)



#### Note 3:

- a) The power dissipation and thermal resistance values are shown for a single device (During single-device operation, power is only applied to one device.)
- b) The power dissipation and thermal resistance values are shown for a single device (During dual operation, power is evenly applied to both devices.)

Note 4: V<sub>DD</sub> = -24 V, T<sub>ch</sub> = 25°C (Initial), L = 1.0 mH, R<sub>G</sub> = 25  $\Omega$ , I<sub>AR</sub> = -3.5 A

- Note 5: Repetitive rating: pulse width limited by maximum channel temperature
- Note 6: on lower left of the marking indicates Pin 1.



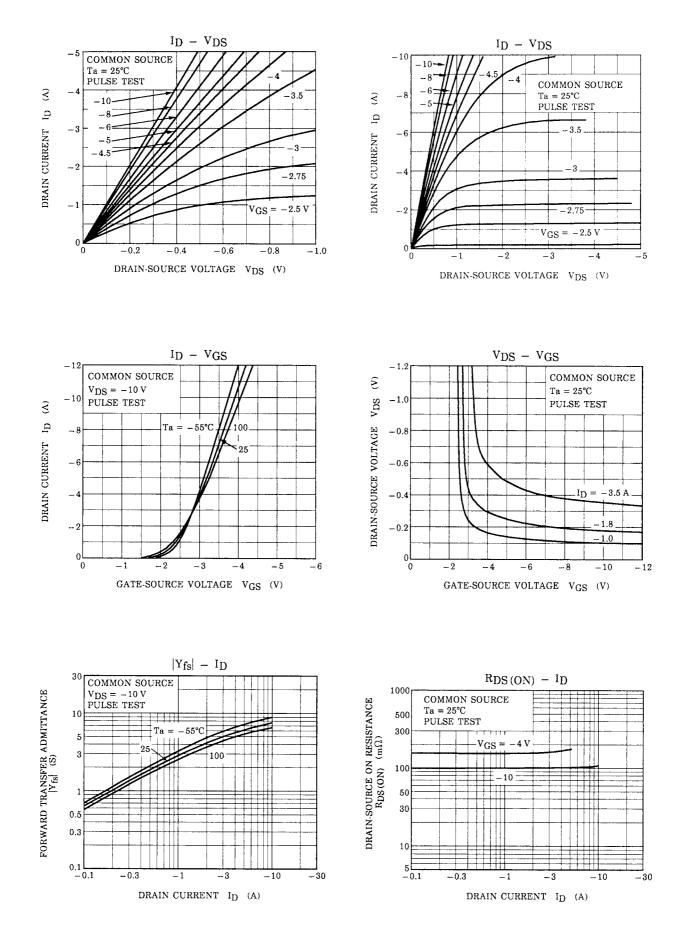
Electrical Characteristics (Ta = 25°C)

Charao	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	urrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V	_	_	±10	μA
Drain cut-OFF	current	I <sub>DSS</sub>	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$			-10	μA
Drain-source br	reakdown voltage	V (BR) DSS	I <sub>D</sub> = -10 mA, V <sub>GS</sub> = 0 V	-30	_	_	V
Gate threshold	voltage	V <sub>th</sub>	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -1 \text{ mA}$	-0.8		-2.0	V
Desire assures O	Nunciataria	R <sub>DS (ON)</sub>	V <sub>GS</sub> = -4 V, I <sub>D</sub> = -1.8 A	— 155 190		190	
Drain-source O	IN resistance	R <sub>DS (ON)</sub>	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -1.8 A	_	95	120	mΩ
Forward transfe	r admittance	Y <sub>fs</sub>	V <sub>DS</sub> = -10 V, I <sub>D</sub> = -1.8 A	2	4	_	S
Input capacitance	ce	C <sub>iss</sub>			540	_	
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = −10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	80	_	pF
Output capacitance		C <sub>oss</sub>			290	_	
Gate threshold voltage Vth   Drain-source ON resistance RDS (G   Forward transfer admittance  Yfs   Input capacitance Ciss   Reverse transfer capacitance Crss   Output capacitance Coss   Output capacitance Coss   Switching time Rise time tr   Fall time tf   Turn-OFF time toff   Total gate charge (Gate-source plus gate-drain) Qg	Rise time	tr	$V_{GS 0V} \bigcup_{i=10}^{I_{D} = -1.8A} V_{OUT}$		11	_	
	t <sub>on</sub>			17	_		
	Fall time	t <sub>f</sub>	*# # 6		11	_	- ns
	Turn-OFF time	t <sub>off</sub>	$V_{DD} = -15 V$ Duty $\leq 1\%$ , t <sub>w</sub> = 10 $\mu$ s	_	70	_	
		Qg	V <sub>DD</sub> ≈ −24 V, V <sub>GS</sub> = −10 V, I <sub>D</sub> = −3.5 A	_	18	_	
Gate-source charge		Q <sub>gs</sub>		_	13		nC
Gate-drain ("miller") charge		Q <sub>gd</sub>	]		5		

# Source–Drain Ratings and Characteristics (Ta = 25°C)

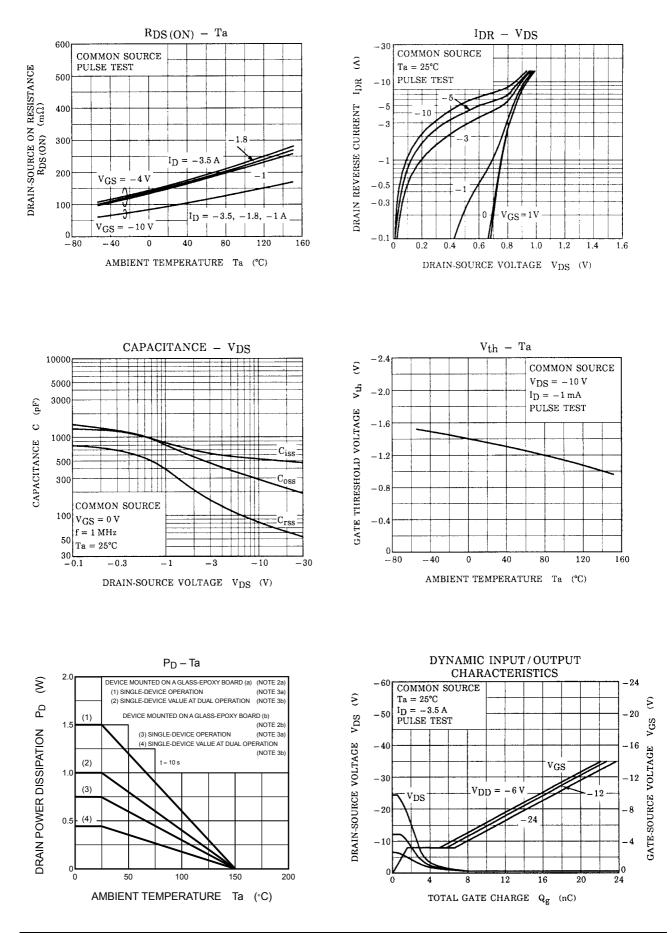
Charact	teristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I <sub>DRP</sub>	—	_	_	-14	А
Forward voltage	(diode)	V <sub>DSF</sub>	I <sub>DR</sub> = -3.5 A, V <sub>GS</sub> = 0 V			1.2	V

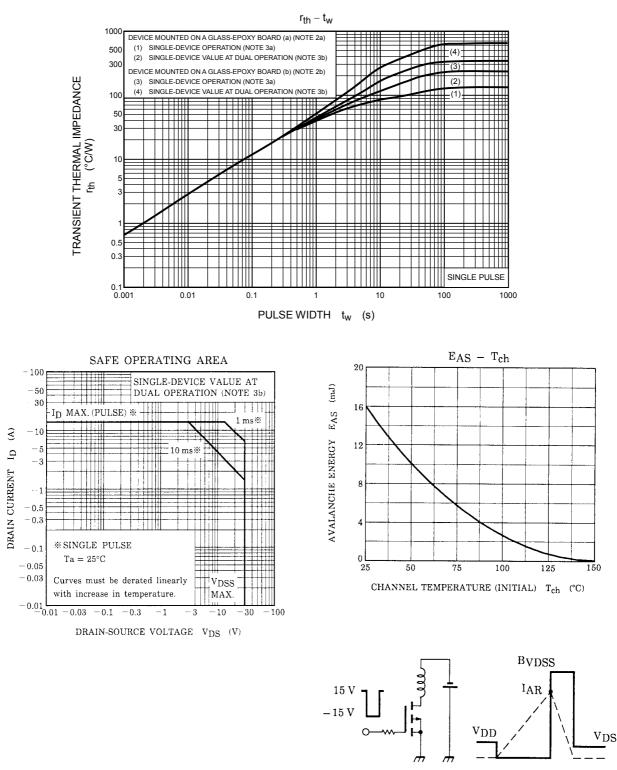
# TOSHIBA



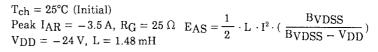
2003-02-18

# TOSHIBA





TEST CIRCUIT WAVE FORM



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